

## Restricted Substances in Materials: Testing and Reporting Procedures Workshop October 5 – 7, 2005

Hosted by  
The National Institute of Standards and Technology

### Wednesday, October 5

Red Auditorium

**Registration Opens** **11:00 am**

**Welcome and Opening Remarks** **1:00 pm**

#### **Afternoon Plenary Session**

- The Role of NIST in Support of US Industry and Global Comparability  
W. May, NIST Chemical Science and Technology Laboratory
- Impact of Regulated Substance & Environmental Legislation on the Electronics Industry  
J. Johnson, Cisco Systems
- RoHS Implementation – A view from an Engineering Polymers supplier  
E. Beyeler, DuPont Engineering Polymers
- The Restriction of Hazardous Substances (RoHS) Directive – enforcement in the UK and across Europe  
S. Andrews, Dept. of Trade & Industry, UK

**EVENING RECEPTION** **6:00 – 7:30 pm** *Hall of Flags*

### Thursday, October 6

Red Auditorium

**Morning Plenary Session: Declaration Standards** **9:00 am**

- The Impact of Emerging Substance Regulations - Strategies for Product Environmental Compliance  
E. Karofsky, AMR Research
- Materials Declaration  
F. Abrams, IPC

**BREAK (15 minutes)** **10:40 am**

#### **Panel Discussion on Industry Perspective**

- Supplier Declarations Under EU's RoHS Directive C. Bell, Sidley, Austin, Brown & Wood
- Collaborative Automotive Industry Initiatives, Material Declaration - A Working Example  
M. Fisher, APC/ACC
- Supply Chain Material Disclosure J. Dills, The GoodBye Chain Group

Issues in Material Composition Reporting F. Rossman, Jabil Circuit  
Restricted Substances Data Exchange: Large and Small Company Perspectives  
J. Shepherd, Canyon Snow Consulting

**LUNCH** **12:45 pm** *Cafeteria*

**Afternoon Plenary Session: Test Method & Reference Materials** **2:00 pm**

- IEC TC111 Working Group 3  
J. Johnson, Cisco Systems
- ASTM International Committee F40 on Declarable Substances  
T. McGrady, IMR Test Labs

**BREAK (15 minutes)** **3:20 pm**

**Panel Discussion on Substances and Test Methods**

Contributing Work to the XRF Screening Method R. Wopperer, Oxford Instruments  
The Referee Analyses - How Good are They? Stanislaw Piorek, Thermo Electron  
Flame Retardants – Issues of Relevance to Environmental Regulations D. Edenburn, Edenburn Consulting International  
The Hexavalent Chromium Challenge S. Lau, IBM Systems and Technology Group  
Analysis of Mercury in Materials T. McGrady, IMR Test Labs  
RoHS-related CRM activities of IRMM T. Linsinger, Joint Research Centre, Institute for Reference Materials and Measurements

**TRANSPORTATION** **6:30 pm**

**Friday, October 7** **Lecture Room B**

**Morning Plenary Session: Program Planning** **9:00 am**

- **Moderated Discussion**  
Topics:  
Report from Declaration Standards Session  
E. Simmon, NIST Electronics and Electrical Engineering Laboratory  
Report from Test Method and Reference Materials Session  
J. Sieber, Chemical Science and Technology Laboratory  
Prioritization of Certified Reference Materials  
Prioritization of Test Method Development Issues

**BREAK (15 minutes)** **10:30 am**

- **Continued Discussion and Documentation**

**ADJOURNMENT**

**12:00 pm**